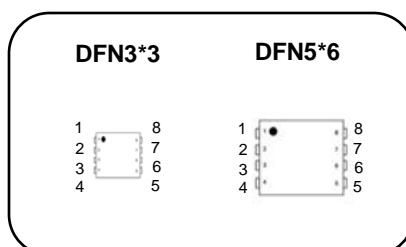
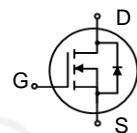


N-channel Enhanced mode DFN3*3/DFN5*6 MOSFET**Features**

- High ruggedness
- Low $R_{DS(ON)}$ (Typ 6.8mΩ)@ $V_{GS}=4.5V$
(Typ 5.7mΩ)@ $V_{GS}=10V$
- Low Gate Charge (Typ 25nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application:DC-DC Converter,Motor Control,
Synchronous Rectification

**4.Gate 5,6,7,8.Drain
1,2,3.Source**

BV_{DSS} : 30V
I_D : 20A
R_{DS(ON)} : 6.8mΩ@V_{GS}=4.5V
5.7mΩ@V_{GS}=10V

**General Description**

This power MOSFET is produced with advanced technology of SAMWIN.

This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW H 055R03VT	SW055R03V	DFN3*3	REEL
2	SW HA 055R03VT	SW055R03VT	DFN5*6	REEL

Absolute maximum ratings

Symbol	Parameter	Value		Unit
		DFN3*3	DFN5*6	
V _{DSS}	Drain to source voltage	30		V
I _D	Continuous drain current (@T _a =25°C)	20*		A
	Continuous drain current (@Ta=100°C)	12.6*		A
I _{DM}	Drain current pulsed (note 1)	80		A
V _{GS}	Gate to source voltage	±20		V
E _{AS}	Single pulsed avalanche energy (note 2)	83		mJ
E _{AR}	Repetitive avalanche energy (note 1)	8		mJ
dv/dt	Peak diode recovery dv/dt (note 3)	5		V/ns
P _D	Total power dissipation (@Ta=25°C)	2.9	3.2	W
	Derating factor above 25°C	0.02	0.03	W/°C
T _{STG} , T _J	Operating junction temperature & storage temperature	-55 ~ + 150		°C

*. Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Value		Unit
		DFN3*3	DFN5*6	
R _{thja}	Thermal resistance, Junction to ambient	43	39.6	°C/W

Note: R_{thja} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{thjc} is guaranteed by design while R_{thca} is determined by the user's board design. DFN3*3 R_{thja} : 43°C/W on a 1 in² pad of 2oz copper.

DFN5*6 R_{thja} : 39.6°C/W on a 1 in² pad of 2oz copper.

Electrical characteristic (Ta = 25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
Off characteristics						
BV _{DSS}	Drain to source breakdown voltage	V _{GS} =0V, I _D =250uA	30			V
ΔBV _{DSS} / ΔT _J	Breakdown voltage temperature coefficient	I _D =250uA, referenced to 25°C		0.02		V/°C
I _{DSS}	Drain to source leakage current	V _{DS} =30V, V _{GS} =0V		1		uA
		V _{DS} =24V, Ta=125°C		50		uA
I _{GSS}	Gate to source leakage current, forward	V _{GS} =20V, V _{DS} =0V		100		nA
	Gate to source leakage current, reverse	V _{GS} =-20V, V _{DS} =0V		-100		nA
On characteristics						
V _{GS(TH)}	Gate threshold voltage	V _{DS} =V _{GS} , I _D =250uA	1.0		1.8	V
R _{DS(ON)}	Drain to source on state resistance	V _{GS} =4.5V, I _D =10A, T _j =25°C		6.8	8.5	mΩ
		V _{GS} =10V, I _D =10A, T _j =25°C		5.7	7.1	mΩ
		V _{GS} =4.5V, I _D =10A, T _j =125°C		10		mΩ
		V _{GS} =10V, I _D =10A, T _j =125°C		8.5		mΩ
G _f	Forward transconductance	V _{DS} =5V, I _D =10A		40		S
Dynamic characteristics						
C _{iss}	Input capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz		2140		pF
C _{oss}	Output capacitance			327		
C _{rss}	Reverse transfer capacitance			261		
t _{d(on)}	Turn on delay time	V _{DS} =15V, I _D =14A, R _G =4.7Ω, V _{GS} =10V (note 4,5)		9.4		ns
t _r	Rising time			59		
t _{d(off)}	Turn off delay time			57		
t _f	Fall time			16		
Q _g	Total gate charge	V _{DS} =25V, V _{GS} =4.5V, I _D =14A (note 4,5)		25		nC
Q _{gs}	Gate-source charge			4		
Q _{gd}	Gate-drain charge			13		
R _g	Gate resistance	V _{DS} =0V, Scan F mode		1.8		Ω

Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I _S	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			20	A
I _{SM}	Pulsed source current				80	A
V _{SD}	Diode forward voltage drop.	I _S =20A, V _{GS} =0V			1.4	V
t _{rr}	Reverse recovery time	I _S =20A, V _{GS} =0V, dI _F /dt=100A/us		15		ns
Q _{rr}	Reverse recovery charge			2.5		nC

※. Notes

- Repetitive rating : pulse width limited by junction temperature.
- L = 0.32mH, I_{AS} = 23A, V_{DD}=15V, R_G=25Ω, Starting T_J = 25°C
- I_{SD} ≤ 20A, di/dt = 100A/us, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C
- Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%.
- Essentially independent of operating temperature.

Fig. 1. On-state characteristics

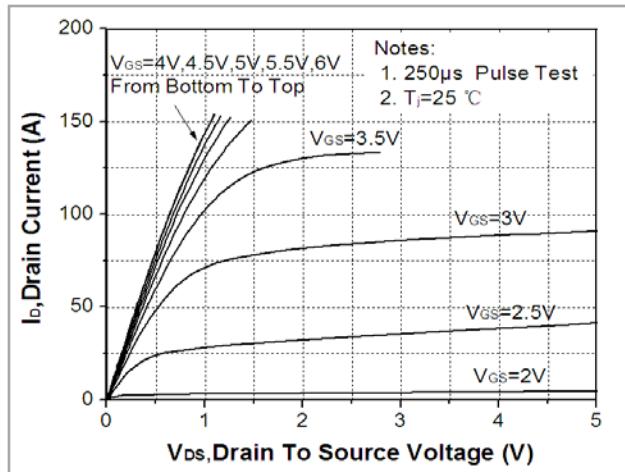


Fig. 2. Transfer Characteristics

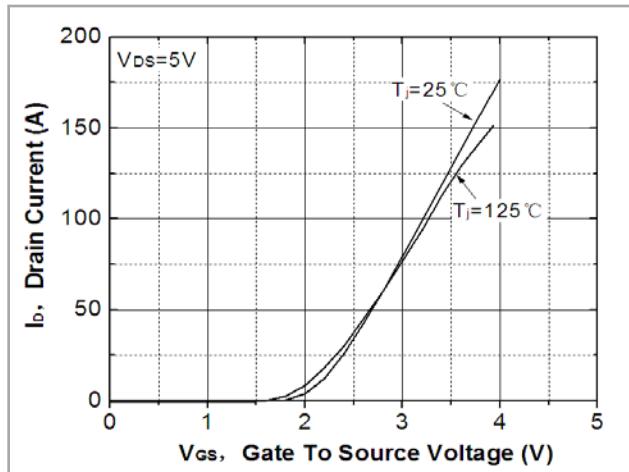


Fig. 3. On-resistance variation vs. drain current and gate voltage

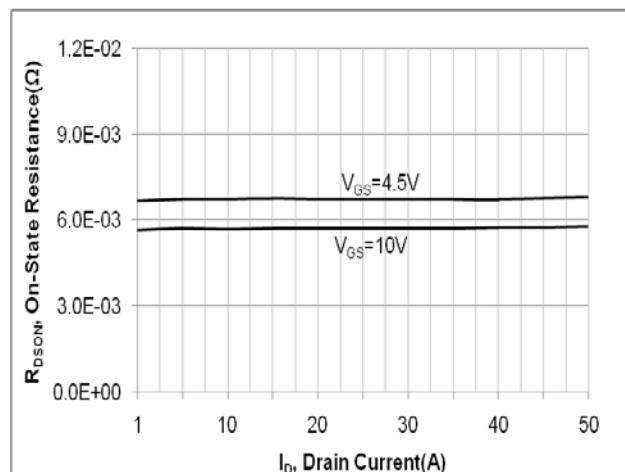


Fig. 4. On-state current vs. diode forward voltage

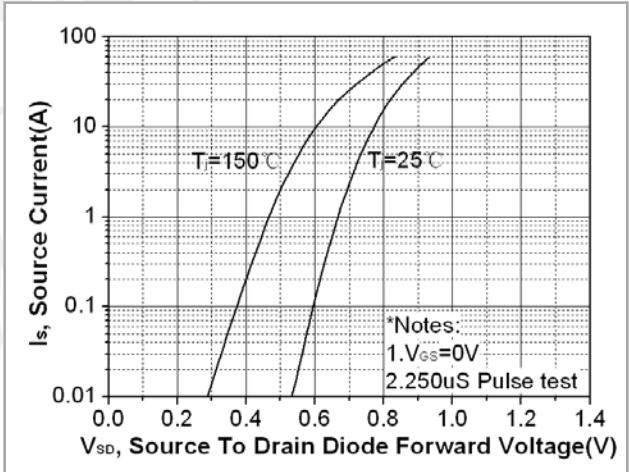


Fig 5. Breakdown voltage variation vs. junction temperature

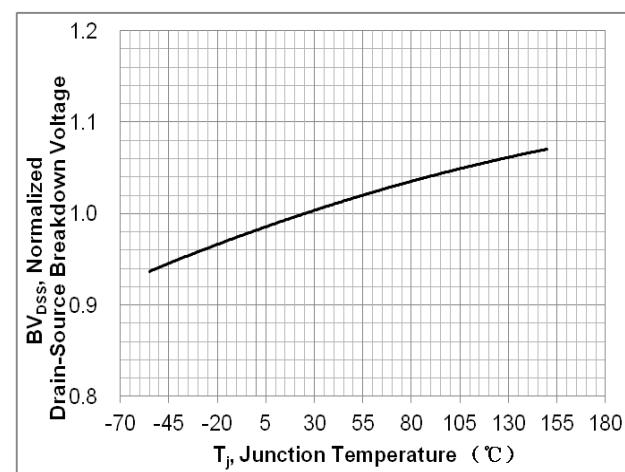


Fig. 6. On-resistance variation vs. junction temperature

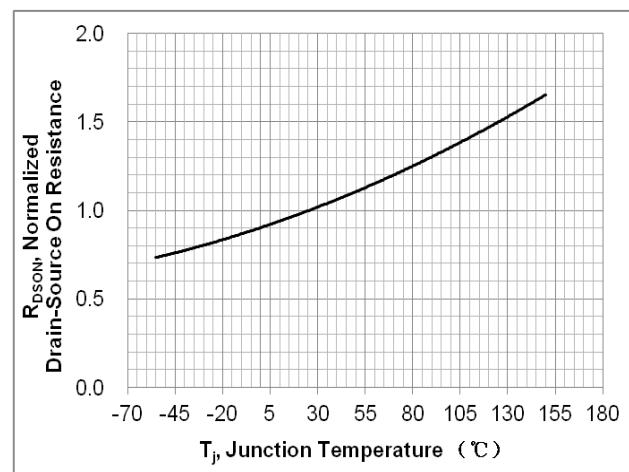


Fig. 7. Gate charge characteristics

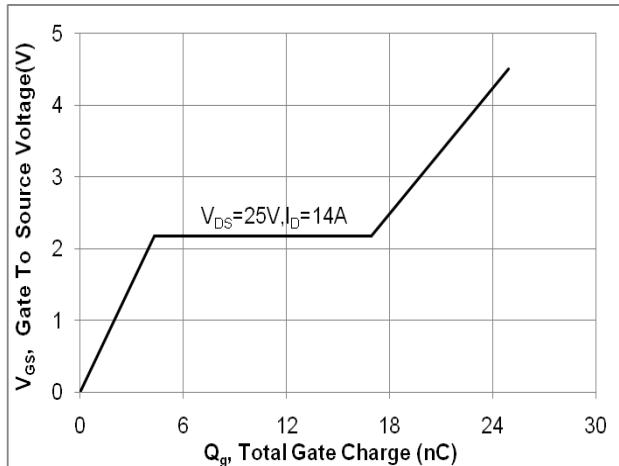


Fig. 8. Capacitance Characteristics

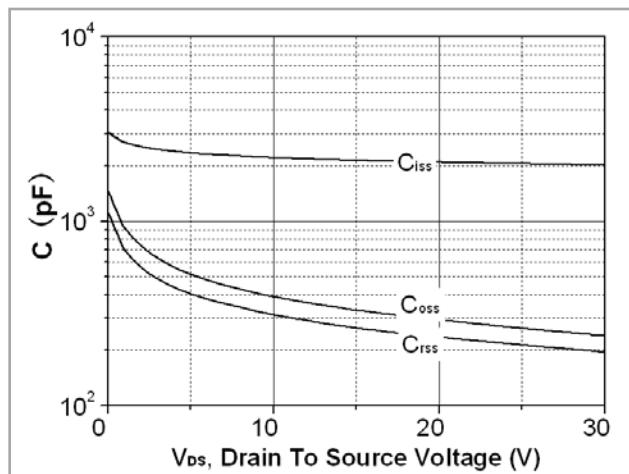


Fig. 9. Maximum safe operating area(DFN3*3)

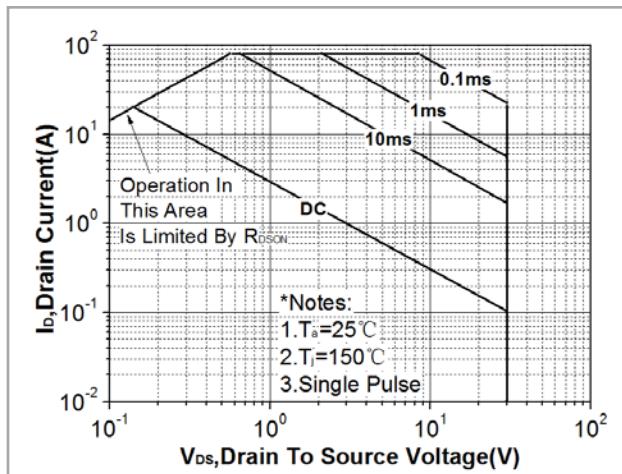


Fig. 10. Maximum safe operating area(DFN5*6)

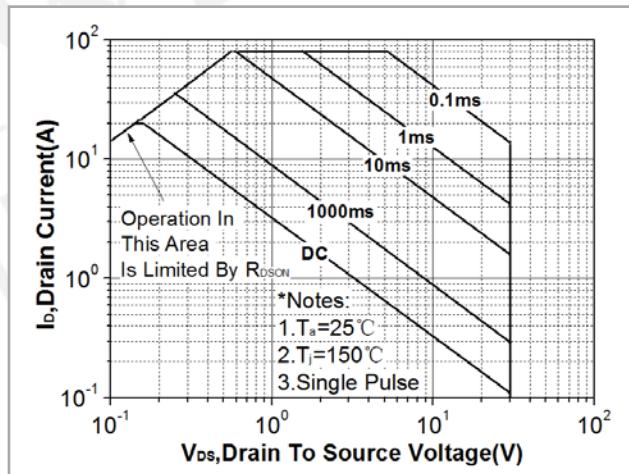


Fig. 11. Transient thermal response curve(DFN3*3)

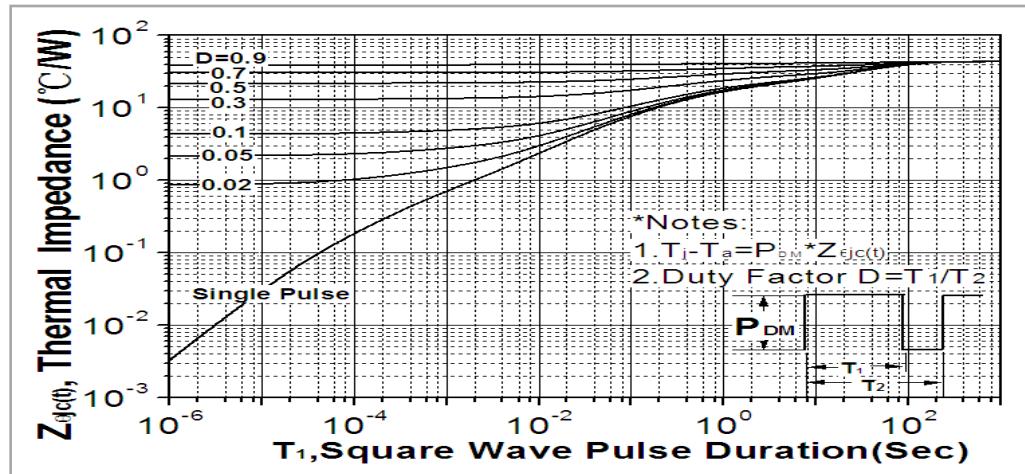


Fig. 12. Transient thermal response curve(DFN5*6)

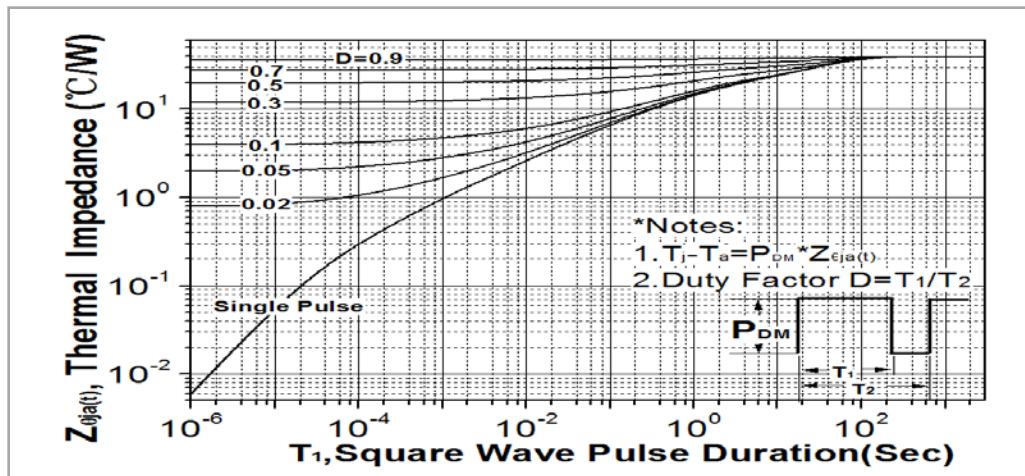


Fig. 13. Gate charge test circuit & waveform

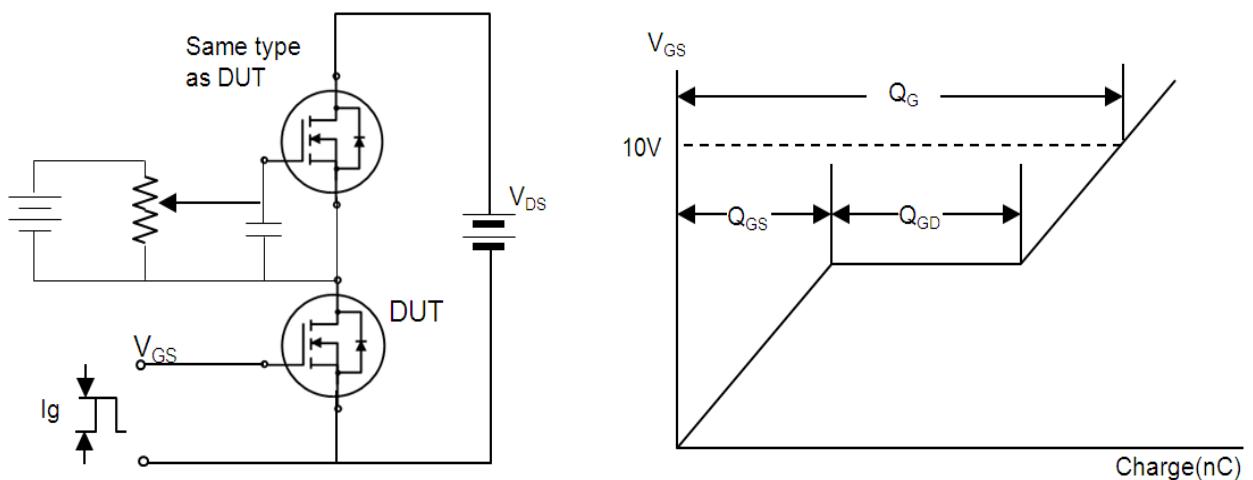


Fig. 14. Switching time test circuit & waveform

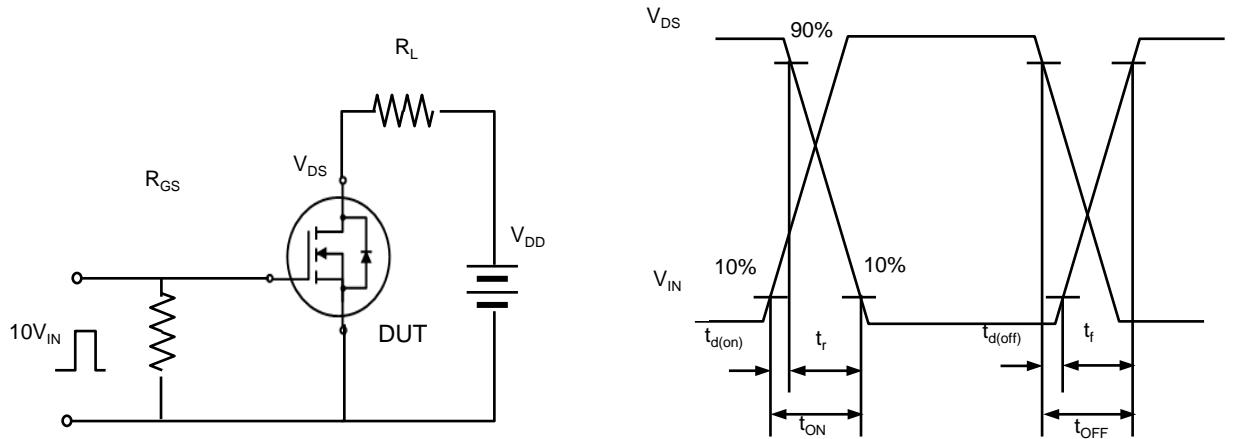


Fig. 15. Unclamped Inductive switching test circuit & waveform

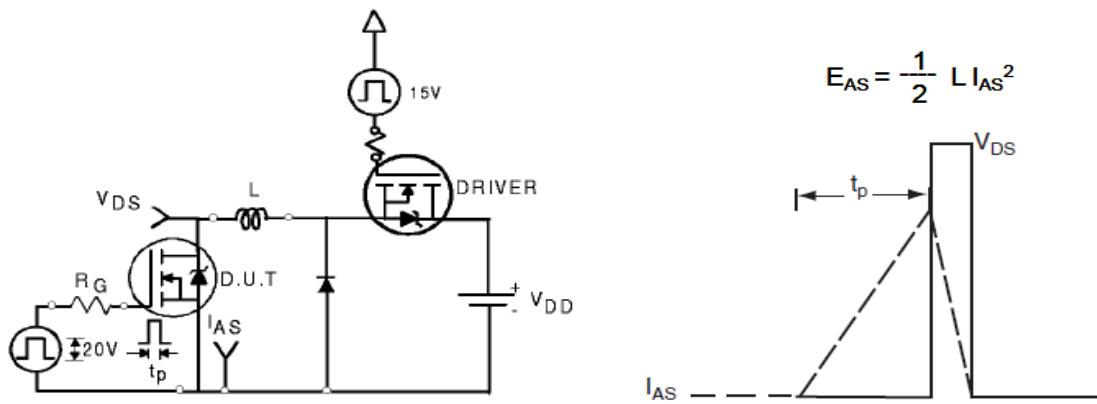
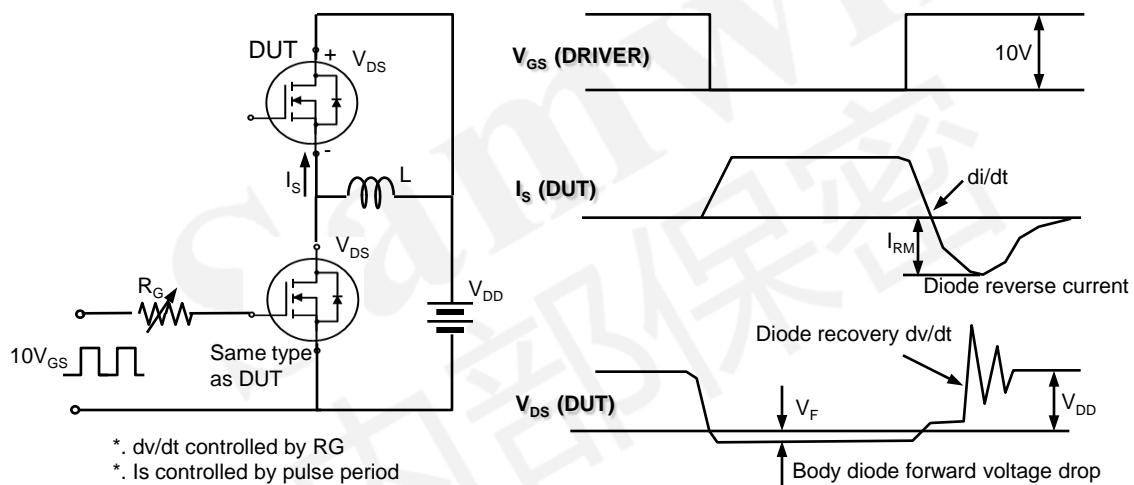


Fig. 16. Peak diode recovery dv/dt test circuit & waveform



DISCLAIMER

- * All the data & curve in this document was tested in XI'AN SEMIPOWER TESTING & APPLICATION CENTER.
- * This product has passed the PCT, TC, HTRB, HTGB, HAST, PC and Solderdunk reliability testing.
- * Qualification standards can also be found on the Web site (<http://www.semipower.com.cn>)
- * Suggestions for improvement are appreciated, Please send your suggestions to samwin@samwinsemi.com

